

# Search Notes



Application/Control No.

10/765,370

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

MCRAE ET AL.

Art Unit

2816

## SEARCHED

Class	Subclass	Date	Examiner
327	108	03-03-05	Hn
	205	T	T
	206		
326	81		
	82		
	83		
	85		
	87		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	03-03-05	Hn
See attachment		